

Notice of References Cited	Application/Control No. 10/719,464	Applicant(s)/Patent Under Reexamination BELLA ET AL.	
	Examiner Tan Dean D. Nguyen	Art Unit 3689	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0049816	04-2002	Costin et al.	709/206
*	B	US-2002/0091538	07-2002	Schwartz et al.	705/1
*	C	US-2002/0188524	12-2002	Shimizu, Hidetaka	705/26
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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